

PROBE, PROBE CARD, AND PROBE MANUFACTURING METHOD

ABSTRACT

5 This probe includes: a first metal portion (N) and
a plate-shaped second metal portion (K). On one end side in
a longitudinal direction X of the first metal portion (K),
the second metal portion (K) is buried along the longitudinal
direction (X) in a predetermined range, and protrudes in the
10 longitudinal direction (X) from the first metal portion (N)
so as to have a contact portion (20c) to contact with an
electrode of a semiconductor device. A cross-section of the
contact portion (20c) perpendicular to the longitudinal
direction (X) has a circular shape, and a cross-section
15 perpendicular to the longitudinal direction (X) at an end of
the second metal portion (K) on a side opposite to the
contact portion (20c) in the longitudinal direction (X) has a
rectangular shape.

20 Figure 2